

Product information

3D surface measurement MarSurf WI 50 M

Product features

High-performance entry-level solution

The MarSurf WI 50 M is a white light interferometer for the three-dimensional measurement and analysis of surfaces – **contactless, independent of material and fast.**

Precise measurement in the sub-nanometer range – simple with the new MarSurf WI 50 M, the perfect entry-level solution. The system meets all the requirements of your measuring tasks in the nanometer range – offering maximum performance and outstanding value for money. Adjustment and focusing are child#92s play thanks to the functional tilting table and manual X-, Y- and Z-axes.

Key benefits:

- Simple technology without motorized axes
- Intuitive operation
- Fast measurements
- Cost-effective
- Robust and reliable
- Max. sample height 220 mm
- Control unit integrated in tripod

This new optical measuring system is successfully used, for example, for:

- Roughness measurement according to DIN EN ISO 4287 / 25178
- Topography measurement (including volume, wear, isotropy)
- Measurement of microgeometry and layer thicknesses

Users value the reliability of MarSurf series measuring systems as they provide quantitative, **traceable 3D parameters for many** industries.

Application

Mechanical engineering

Qualification and quantification of the roughness, geometry, and wear volume

Electronic system and semiconductors

Component inspection right down to sub-nanometer range for fault-free products



Item no.: **6355000**

Technical data

Resolution	up to 0.2 (nm) vertical
Measuring speed	up to 140 fps
Measuring principle	White-Light-Interferometer High-performance LED (650 nm / white)
Power supplied	100 - 240 V
Surface parameters	ISO 4287, ISO 13565, ISO 25178 ...
Weight	0 KG